PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc., has assessed the Laboratory of:

EMI Gage
28W144 Industrial Avenue Suite 100
Lake Barrington, IL 60010

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025: 2005

This accreditation demonstrated technical competence for the following scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated June 18, 2005):

Calibration in the Laboratory and at Laboratory Controlled Field Sites of Instruments Measuring Surface Texture and Roundness (As detailed in the supplement)

Such testing and/or calibration services shall only be offered at or from the address given above. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

President/Operations Manager

The validity of this certificate is mandated through ongoing surveillance.

Perry Johnson Laboratory Accreditation, Inc. (PJLA)
26555 Evergreen, Suite 1325
Southfield, Michigan 48076

Initial Accreditation Date:	*Issue Date:*	*Expiration Date:*
May 10, 2004	July 10, 2008	July 09, 2010
Accreditation No:	*Certificate No:*	*Page No:*
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Certificate of Accreditation: Supplement

EMI Gage
28W144 Industrial Avenue Suite 100
Lake Barrington, IL 60010

Accreditation is granted to this facility to perform the following calibrations:

CALIBRATION FIELD	MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	BEST MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)
Dimensional	Surface Texture R_a	0.005 µm to 1 mm	$2 \times \sqrt{(0.416^2 + (1.4 \times R_a)^2 + (0.318 \times \text{Std Dev})^2)}$
	Surface Texture R_z	0.100 µm to 1 mm	$2 \times \sqrt{(0.462^2 + (1.4 \times R_z)^2 + (0.318 \times \text{Std Dev})^2)}$
	Roundness Out of Roundness	0 mm to 350 mm	5 nm (0.2 µin)
	Roundness Flick	1.0 µm to 2 mm	$2 \times \sqrt{(0.0166^2 + (0.620 \times \text{Std Dev})^2)}$